Original Research Article

Preliminary Research For Enabling Intelligent Focus For 3D Imaging

8 ABSTRACT

This research was basically on assessing the focus levels of images from tin ball samples as an ideal test. The results and method used for the ideal test sample was then applied to real datasets of samples like the canine kidney cells that have been infected with influenza virus for 24 hours. The tin ball samples and the samples of the influenza virus was viewed with the Dual Focused Ion Beam/ Scanning Electron Microscope (FIB/SEM). The FIB/SEM facility generated images of these samples. The analysis of these images were carried out by measuring the Derivative Sharpness Function in images called the Derivative Sharpness Function using the Digital Micrograph software: the tin ball samples provided perfect results when a pixel difference of 1 was utilized less perfect result for a pixel difference of 20. Also, a defocus increment of 0.01mm was better than a defocus image at 0.001mm displacement. Applying parameters from the successful result of the test samples on real data sets at 0.01mm and a pixel difference of 1 & 10 also produced reasonable results on assessing the levels of focus in real data samples such as the canine kidney cells.

10 11

Keywords: scanning electron microscope, Digital Micrograph, Derivative Sharpness Function, canine kidney cells.

12 13 14

15 **1. INTRODUCTION**

16

17 The aim of this research is to enhance the process of serial sectioning over long periods of taking images of datasets of samples by providing a method that could be the basis of automatic focus adjustment for 18 19 the SEM/FIB. An SEM is a microscope that uses electrons instead of light to produce images. Serial 20 sectioning is simply a process of dissecting a material into thin slices by a Focused Ion Beam, necessary 21 for the SEM to take digital images of every slice therefore giving detailed information about the interior of 22 the material. The materials used in this experiment were tin ball(ideal test) samples and real samples 23 called the canine kidney cells. The kidney cells were stained using Uranium and Osmium based staining 24 agents and encapsulated in epoxy resin. However, the samples do not remain in focus during these long 25 runs serial sectioning on FIB: they tend to drift away from focus and sometimes even get destroyed. 26 Before creating an intelligent technique necessary for creating an automatic focus adjustment of the 27 images that drift out of focus, it is imperative to measure the levels of focus of the images produced 28 during this process which is the primary objective of this research.

29 When a sample is placed in a FIB/SEM, a number of images are generated after several hours 30 (depending on the operator's desire). After sometime of serial sectioning producing images, the quality of the images later obtained is largely reduced: astigmatism is noted and the images are seen not to be in 31 focus as well. This can hinder the process of generating the 3D reconstruction of the 2D images. To 32 33 obtain microstructure parameters of some materials such as Li-ion cell samples, a 3D reconstruction of the several 2D images generated from the FIB/SEM is required using image processing softwares such 34 35 as Avizo [1],[2]. Since at least, 50 2D images are needed to get reasonable information from the 36 microstructure parameters about the material, the quality of the 2D images is also very important, hence 37 the need to find an automated process for enhancing the quality of the 2D images is imperative.

38 2. MATERIAL AND METHODS

39

This section discusses the method used in obtaining images from tin ball samples and the canine kidney cells from the dual FIB/SEM, as well as the software (Digital Micrograph) utilized in processing the images and the method used in analysing the images in the Digital Micrograph.

43 **2.1 Focused Ion Beam/Scanning Electron Microscope**

The Focused Ion Beam in a FIB/SEM dual system slices the samples of the tin balls and canine kidney cells into thin samples for the Scanning Electron Microscope to take images [3],[4]. This is necessary because electrons have low penetration depth; therefore, thin samples are needed for the SEM to provide highly resolved spatial details of these samples. The dual FIB/SEM system was at *5.0 kV* and 0.40 nA during serial sectioning and with a magnification value of 5000*X* for tin ball samples. By adjusting the focus knobs on the SEM, defocused images were gotten. A schematic diagram of the dual FIB/SEM is shown in Figure 1.



51 52

Figure 1 | A schematic diagram of the dual FIB/SEM. The angle between the FIB and SEM beams is 52° , with the ion beam at 90° to the specimen

54 55

53

56 By defocusing, we were simply adjusting the focusing lens and consequently expanding the size of the spot that is scanned across the sample, therefore features in the image became less sharply resolved. At 57 0 mm the image was in focus and millimetres away from zero, the images were in defocus. For focus and 58 defocus datasets of images were obtained, with the first run having a defocus increment of 0.01 mm, the 59 60 second, third and fourth run had 0.01 mm, 0.005 mm and 0.001 mm respectively. The experimental set 61 up for the biological samples(canine kidney cells) was operated at the same condition(Voltage and 62 Current) for the tin ball samples, but the magnifications were different i.e. the same set of biological 63 samples in two different magnification values: 7500X three times at different defocus levels and 15000X, 64 five times for different defocus levels. The defocus values for the former magnification values are:

0.01 *mm*, 0.005 *mm* and 0.001 *mm*. For the latter magnification, the defocus values were: 0.01 *mm*,0.005
 mm,0.001 *mm*, 0.001 *mm* and 0.005 *mm*. The experiment was repeated to ensure all the defocus values
 used were exactly the same with that for the tin ball samples, hence, the repeated defocus values.

Fig. 2a, shows an image in focus, while Fig. 2b, 2c and 2d depict SEM images that are 0.01*mm*, 0.02*mm* and 0.03*mm out* of focus respectively.



Figure 2 | SEM images of tin ball samples at different focus and defocus modes. (a) in focus 0.00mm(b) defocus 0.01mm (c) defocus 0.02mm (d) defocus value 0.03mm (e) defocus value 0.06mm (f) defocus value 0.07mm.

Looking at the images above, it is observed that the image in Fig. 2a is sharp and has no streak or blur. As seen from figure 2b to 2d the blurriness increases. This is due to increment in defocus values. The images in Figure 2(e) and 2(f) further illustrate the defocus concept using some of the pictures of the images. The images in Figures 2(e) and 2(f), further show that as the defocus value increases, so does the blurriness in the images increase.

84 2.2. DIGITAL MICROGRAPH

The Digital Micrograph is an image acquisition and processing software that provides SEM and Transmission Electron Microscope (TEM) users a complete package to also analyze and present image and spectrum data. The functionality of a Digital Micrograph enables image processing tasks of all sorts to be accomplished using the powerful built-in C++ like script [5]. The software was extensively used in this project to process the data sets of images collected from the FIB/SEM. We started by using this software to calibrate each of the focus/defocus images which were originally 884 by 884 pixels to 1024 by 884 pixels. Fourier Transforms of each of the images was also gotten using this software. Written scripts were used to determine the Derivative Sharpness Function of defocus/focus datasets of images.

93 The process of finding the value of the derivative of a function is known as numerical differentiation. 94 The derivative of a function represents the infinitesimal change with respect to one of its variables [6]. 95 which are the pixels of each of the images in this research. Sharpness Function is a real-valued estimation of discrete image sharpness. There are several methods used in deriving the Sharpness 96 97 Function of an image. They are: the Derivative based Sharpness Function, Fourier transform based 98 sharpness function, statistical based sharpness function. Among the different ways of evaluating sharpness function of images, it was investigated that the derivative based sharpness function and the 99 100 Fourier transform based sharpness function were the best methods in evaluating this function. The 101 derivative sharpness function, measures the intensity differences between neighbouring pixels of a 102 defocus image. The mathematical equation for the DSF is shown below:

 $DSF = \sum_{i,j} |f_{i,j} - f_{i,j+k}|^p$ where $p \in \{1,2\}$, i, j = 1024,884 & k is the pixel difference.

105

106 where *f* is a function of the pixel values in the vertical , (*i*) and horizontal, (*j*) axes of the images. *p* is 107 known as the Brenner function. p = 1 was used to carry out the experiments.

Only the pixel difference taken in the horizontal distance is taken into account due to the fact that SEM scan is done only in the horizontal direction. DSF shows the effects of defocus by varying the pixel parameter in an axis. The images of the tin ball samples were originally $f_{1024,884}$. The displacement of the image became $f_{1024+k,884}$. The k values used in this experiment were 1,10,20 and 50. When $f_{1024+k,884}$ is subtracted from $f_{1024,884}$, the intensity difference between each of the neighboring pixels is obtained which is smaller in defocused images. The summation of the intensity differences gives the value of the DSF. The difference between pixels in an image is maximum when in focus.

116 3. RESULTS AND DISCUSSION

117

The method of DSF using the Digital Micrograph software was used to process the images one at a time and the corresponding derived images from the processed images are depicted in Figure 3. The images were first displaced at a pixel difference of 1 on the x-axis to give1025 *against* 884. The displaced images were subtracted from the original ones and then summed up to give DSF images with their corresponding values.





128gk129Figure 3 | Resulting images from the Digital Micrograph after processing using the Derivative130Sharpness Function script. (a) 0.00mm(b) 0.01mm (c) 0.02mm. At a pixel difference of 20 | (d)1310.00mm (e) 0.01mm (f) 0.02mm (g) 0.08mm (h) 0.09mm (k) 0.10mm

132

126 127

Figure 3a is the DSF of an in-focus image of the tin ball samples, Fig. 3b is the DSF image 0.01mm out of focus. Fig. 3c, shows the DSF image 0.02mm. The images of Fig. 3b and 3c show traces of the tin ball samples while the DSF image in-focus does not. This is probably because the pixel difference of the defocused images is small i.e. 1. Carrying out the same method at a pixel difference of 20, shows a different perspective about the DSF.

Figure 3d shows the DSF of an in-focus image, while Fig. 3e and f show the DSF of images that are out of focus. Compared to the images in Fig. 3a, b and c, dark representation of the tin ball samples is shown even at when in-focus. Taking the DSF of defocused image of higher values to illustrate more on this experiment was imperative.

142 The DSF images as shown in Figures 3 g, h and k are defocused images of values 143 0.08mm, 0.09mm & 0.10mm. They are not as bright as the DSF images in Figures 3d, e & f. This may 144 be due to the low intensity differences in these highly defocused images. The value of the DSF is smaller 145 in these images.

Using MATLAB [7], graphs of values of the DSF against the defocus increment were plotted as shown
in the next page of the report. The reason for picking this *k* values was just to evaluate if a better result
will be obtained at a higher *k* value than a lower value.





С

Figure 4 | Plot of DSF values against defocus increment 0.01mm for (a) pixel difference (k) of 1
(b) pixel difference (k) of 20. Defocus increment 0.001mm (c) pixel difference of 1 (d) pixel difference(k) of 20.

155

151

Figures 4a and b show graphs of the various DSF values against their respective defocus values. At a pixel difference of 1, as shown in Figure 4a the graph is more strongly peaked at the in-focus value 0*mm.* Both graphs have higher DSF values when in-focus than when they are out of focus. The DSF values against the defocus increment at a pixel difference of 20 are slightly evenly distributed compared to the pixel difference of 1 which have DSF values below 6.4 in the range 0.04mm - 0.10mm and -0.04mm to - 0.10mm too. This showed that the DSF method showed better results at 20 pixel differences.

163 It was imperative to test the outcome of the results obtained when at the same pixel differences as the 164 previous sub-section results have shown. In this experiment, a small value of defocus increment is 165 worked on. The values of the DSF were plotted against an arithmetic series of 0.001*mm* respective 166 defocus increment values as shown in the graphs.

The graphs of defocus series 0.01mm and 0.001mm at pixel differences of 1 & 20 are similar 167 because of the peak defocus values the two of them have. In the DSF graphs of 0.001mm, the graphs 168 are not strongly peaked at the 0.00 mm(in-focus) but at 0.003 mm. The DSF values in the 0.01 mm 169 defocus values are not evenly distributed compared to the DSF graphs of 0.01mm shown in Figures 4a 170 171 &b. Figure 4b graph is more strongly peaked at 0.003 mm, which indicates better results when k is > 1. 172 Furthermore, comparing the results showed finding the Derivative Sharpness Function at a defocus value 173 of 0.01 mm produces important results compared to smaller defocus values of 0.001mm, that is, the DSF 174 values with respect to their individual defocus values are evenly distributed and can provide useful 175 information about defocus/focus levels of images.

As analyzed in the sections above to acquire useful, practical results about when best the Derivative Sharpness Function is ideal and best fit to measure the levels of focus/ defocus intensities in images, we

then look at the possibility of applying the best fitted method on the canine kidney cells(biological cells).

179 Below are sample images of the kidney cells:



180 181



183 184

(b)



185 186

187

(c)

Figure 5 | SEM images of canine kidney cells. (a) in focus (0.00mm) (b) out of focus (0.05mm) (c)
 out of focus (-0.05mm)

190 Figures 5 a, b &c, are SEM images of the sample in cross-section after a trench has been opened and the face polished by the FIB. The image in Figure 5a was in focus while the images of Figure 5 b & c 191 192 were out of focus. The images had the same number of pixels(1024 by 884) as the tin ball samples and there was no need for calibration: scanning of images by the SEM on these samples were applied in the 193 horizontal direction, a different approach was utilized in deriving the Derivative Sharpness Function for 194 195 each of the images. The pixel difference was added on the horizontal axis and not in the vertical axis as 196 equally carried out in the tin ball sample experiment. This was because of the position in which the canine 197 kidney cells were placed in the SEM. To find the DSF, images were replicated and then displaced by a pixel difference of 1 & 10 in the horizontal axis to give images having (1024,885) pixels and (1024,894) 198 199 pixels respectively. These new images were then subtracted from the original image and the summation 200 of the result of the pixels was derived.



201 202

(a)

203

204 205

206



207 208 209

Figure 6 | DSF images of the canine kidney cells at (a) in focus (0.00mm) (b) out of focus (0.05mm) (c) out of focus (-0.05mm)

210 211 212

The DSF images of all the samples do not give reasonable resolved details of the cell as shown in images in Figure 6 a, b & c above. This is basically due to the original size of cells compared to tin ball samples. They are much smaller, therefore finding the DSF reduces the effect of using our natural eyes to see the details. Despite this, the values of the DSF gave some useful results as shown in the graphs in the next section.

Using MATLAB again, to plot graphs, the DSF results against each of its individual defocus value is depicted in Figure 7



220 221

222

223

224

Figure 7 | Plot of DSF values against defocus increment 0.01mm for (a) pixel difference (k) of 1 (b) pixel difference (k) of 10

The graphs above show the DSF values against the defocus increment 0.01*mm* at pixel differences of 1 and 10 when the magnification was 7500X. The graph show a reasonable result similar to the result obtained in the graphs of figure 5a&b. Although at a pixel difference of 10 it shows the same values of DSF between focus and 0.01*mm* away from focus. The graphs are also strongly double-peaked which is not noticeable in the

- results of the ideal tin ball samples.
- 231 232
- 233 4. CONCLUSION
- The Derivative Sharpness Function against the defocus series of tin ball samples, which are ideal samples was shown to give results that are reasonable in measuring the focus/
- defocus levels of images. When the best result was obtained at a defocus difference of
- 237 0.01 *mm*, this value was applied to real samples: the canine
- kidney cells. It showed a considerable measurement of the levels of focus/ defocus levelsof images.
- 240 However, the DSF values obtained from a pixel difference of 1 when compared
- to a pixel difference of 10 and 20 were in values of hundreds, that it
- 242 was quite difficult to use the program MATLAB to plot the DSF data obtained in these
- range on the same graph. Better results were obtained when the pixel difference is
- greater than 1. More research needs to be done in measuring levels of focus/defocus in images
 obtained from the FIB/SEM at pixel differences greater than 20. C++ codes that can be used in the
 FIB/SEM dual system needs to be written based on useful results obtained from this research and be
- ran on the system to reduce the level of drifts seen in images during the process of serial sectioning.
- 248 249

250 **REFERENCES**

- 251 1. Jochen, J. et al, Reconstruction of porous electrodes by FIB/SEM for detailed microstructure modelling.
 252 *Journal of Power Sources*, 2011:96
- 253 2. Jui-Ching Lin et al, Three-Dimensional Characterization of Pigment Dispersion Paint Films using 254 Focused Ion Beam-Scanning Electron Microscopy. *Microscopy and Microanalysis*, 2012:18, 266-271.
- 255 3. McGrouther, D & Munroe, P.R. Imaging and Analysis of 3D Structure Using a Dual Beam FIB. 256 *Microscopy Research and Technique*, 2007:70,186-194.
- 257 4. Gatan online. *Digital Micrograph*, 2012. Accessed:10 January,2014. Available from: 258 <u>http://www.gatan.com/imaging/dig_.php</u>.
- 259 5. P.J. Grundy and G.A. Jones, *Electron Microscopy in the study of Materials*, Edward Arnold(publishers)
 260 limited, 1976.
- 261 6. Rudnaya, M.E. et al, Evaluating Sharpness Functions for automated scanning electron microscope.
 262 *Journal of Microscopy*,2010:240,38-39.
- 263 7. Wolfram Mathworld. *Derivatives*, 2014. Accessed: 10, January 2014. Available from: <u>http://mathworld.wolfram.com/Derivative.html</u>.
- 265
- 266